

<b>Notic of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
		Examiner Ronald W Leja	Art Unit 2836	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,055,847	10-1977	Fletcher et al.	257/34
	B	US-5,750,473	05-1998	Shen, Zhi-Yuan	505/210
	C	US-6,552,415	04-2003	Paul et al.	257/661
	D	US-4,963,852	10-1990	Drehman, Alvin J.	505/191
	E	US-5,053,383	10-1991	Short et al.	505/325
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 1 383 178 A1	01-2004	EPO	Decroux et al.	H01L 39/16
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	US 2003/0080849 A1 Chen et al.
	V	M. Lindmayer, Current Limiting Properties of YBCO-Films on Sapphire Substrates, IEEE Transactions on Applied Superconductivity, Vol. 9, No. 2, June 1999.
	W	M. Decroux, Properties of YBCO Films at High Current Densities: Fault Current Limiter Implications, IEEE Transactions on Applied Superconductivity, Vol. 11, No. 1, March 2001.
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.